

Patent

Customer No.: 31561  
 Docket No. 11535-US-PA  
 Application No.: 10/605,357

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Applicant : CHANG et al.  
 Application No. : 10/605,357  
 Filed : 2003/09/25  
 For : METHOD FOR DETECTING DEFECT OF  
 SEMICONDUCTOR DEVICE  
 Art Unit : 2822  
 Examiner : NOVACEK, C.L.

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JUL 19 2004

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**TRANSMITTAL LETTER**  
 002-1-703-872-9306

(Via fax:10 pages, followed by confirmation copy via courier)

Assistant Commissioner for Patents  
 Arlington, Virginia 22202

Dear Sirs,

In response to the Office Action dated April 19, 2004, please find the relevant paper in response to paper No.04132004. Following the fax transmission, a hard copy via courier will also be forwarded to the Office.

Enclosed documents via courier will include:

- Amendment and Response to Office Action in (8) pages
- Fax confirmation report
- Prepaid return postcard

I believe that no fee is incurred. However, the Commissioner is authorized to charge any fees required in connection with the filing of this paper to account No. 50-2620 (Order No.: 11535-US-PA)

Thank you for your assistance in the subject matter. If you have any questions, please feel free to contact me.

**Patent**

Customer No.: 31561  
Docket No. 11535-US-PA  
Application No.: 10/605,357

Respectfully Submitted,  
JIANQ CHYUN Intellectual Property Office

Date: July 19, 2004

By: Belinda Lee  
Belinda Lee  
Registration No.: 46,863

Please send future correspondence to:  
7F. -1, No. 100, Roosevelt Rd.,  
Sec. 2, Taipei 100, Taiwan, R.O.C.  
Tel: 886-2-2369 2800  
Fax: 886-2-2369 7233 / 886-2-2369 7234  
E-MAIL: [BELINDA@JCIPGroup.com.tw](mailto:BELINDA@JCIPGroup.com.tw); [USA@JCIPGroup.com.tw](mailto:USA@JCIPGroup.com.tw)

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 Application No.: 10/605,357  
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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In Re Application of:	)	
5 CHANG, et al.	)	Examiner: NOVACEK, C. L.
Serial No.: 10/605,357	)	Art Unit: 2822
Filed: 09/25/2003	)	Docket No.: 11535-US-PA
10 For: Method For Detecting Defect Of	)	
Semiconductor Device	)	

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20 No fee is believed to be due in connection with this amendment and response to Office Action. If, however, any fee is believed to be due, the Commissioner is authorized to charge any fees required in connection with the filing of this paper to account No. 50-2620 (order No. 11535-US-PA ).

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**AMENDMENT AND RESPONSE TO OFFICE ACTION**

25 U.S. Patent and Trademark Office  
 Commissioner for Patents  
 2011 South Clark Place  
 Customer Window, Mail Stop **Amendment**  
 30 Crystal Plaza Two, Lobby, Room 1B03  
 Arlington, Virginia 22202

Sir:

35 The Office Action dated 04/19/2004, has been carefully considered. In response thereto, please enter the following amendments and consider the following remarks.